

## Transaction Information

Tool ID	PKG9120
Tool Status	Connected
Location	Burlington, USA
Wafer Size	NA
Fab Section	Test
Tool Available Date	2024-11-04

## General Product Information

Vendor Supplier	Zeiss
Model	NanoFab
Vintage	2015
Serial No	6015
Asset Description	Focus Ion Beam Mill
Software Version	Windows
CIM	NONE
Process	Focus Ion Beam Mill

## Hardware Configuration (Fab)

System Type	Description	Quantity	Status
Main System	FIB tool designed for Packaging and Deep cuts	1	
Factory Interface	NONE		
Options System			
Others			
Handler System	Manual		

## Hardware Configuration (Subfab / Auxilliary Units)

Description	Quantity	Status
NONE		

## Missing/Faulty Parts / Accesories List

Description	Quantity
NONE	

## Tool Pictures

General	NONE
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Hardware Fab

NONE



Hardware Sub-fab

NONE



Manufacture Serial

6015



## Additional Tool Data Files